

N-Channel Trench Power MOSFET

General Description

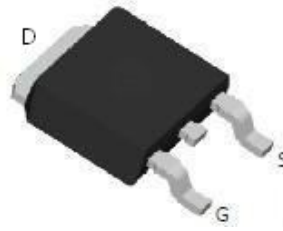
The CSD60N100 combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. Those devices are suitable for use in PWM, load switching and general purpose applications.

Features

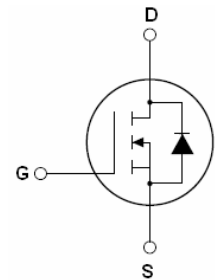
- $V_{DS}=60V$; $I_D=45A$
 $R_{DS(ON)} < 15m\Omega @ V_{GS}=10V$
- Ultra Low On-Resistance
- High UIS and UIS 100% Test

Application

- Power switching application
- load switching



To-252 Top View



Schematic Diagram

$V_{DS} = 60V$

$I_D = 45A$

$R_{DS(ON)} = 11m\Omega$

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|-----------|----------------|-----------|------------|----------|
| CSD60N100 | CSD60N100 | TO-252 | - | - | - |

Table 1. Absolute Maximum Ratings (TA=25°C)

| Symbol | Parameter | Value | Unit |
|-----------------|---|------------|------------|
| V_{DS} | Drain-Source Voltage ($V_{GS}=0V$) | 60 | V |
| V_{GS} | Gate-Source Voltage ($V_{DS}=0V$) | ± 20 | V |
| $I_{D(DC)}$ | Drain Current (DC) at $T_c=25^\circ C$ | 45 | A |
| $I_{D(DC)}$ | Drain Current (DC) at $T_c=100^\circ C$ | 31 | A |
| $I_{DM(pulse)}$ | Drain Current-Continuous@ Current-Pulsed (Note 1) | 180 | A |
| P_D | Maximum Power Dissipation ($T_c=25^\circ C$) | 68 | W |
| E_{AS} | Single Pulse Avalanche Energy (Note 2) | 182 | mJ |
| T_J, T_{STG} | Operating Junction and Storage Temperature Range | -55 To 175 | $^\circ C$ |

Notes 1. Repetitive Rating: Pulse width limited by maximum junction temperature

2. EAS condition: $T_J=25^\circ C, V_{DD}=30V, V_G=10V, R_G=25\Omega$

Table 2. Thermal Characteristic

| Symbol | Parameter | Value | Max | Unit |
|------------------|--------------------------------------|-------|-----|------|
| R _{θJC} | Thermal Resistance, Junction-to-Case | --- | 2.2 | °C/W |

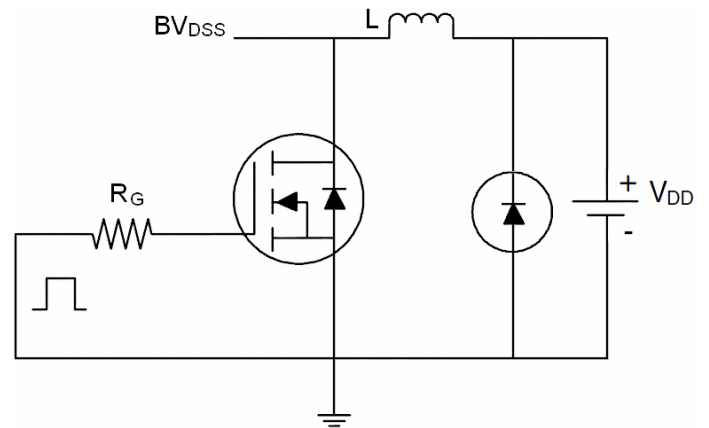
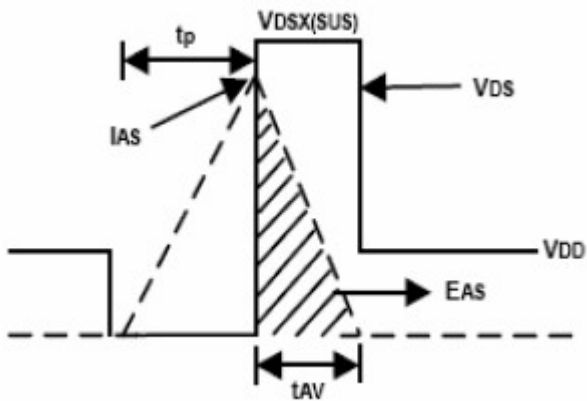
Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|---|---|-----|------|------|------|
| On/Off States | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250μA | 60 | | | V |
| I _{DSS} | Zero Gate Voltage Drain Current(Tc=25°C) | V _{DS} =60V, V _{GS} =0V | | | 1 | μA |
| I _{DSS} | Zero Gate Voltage Drain Current(Tc=100°C) | V _{DS} =60V, V _{GS} =0V | | | 5 | μA |
| I _{GSS} | Gate-Body Leakage Current | V _{GS} =±20V, V _{DS} =0V | | | ±100 | nA |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _D =250μA | 1 | | 3 | V |
| R _{DS(ON)} | Drain-Source On-State Resistance | V _{GS} =10V, I _D =40A | | 11 | 15 | mΩ |
| Dynamic Characteristics | | | | | | |
| g _{FS} | Forward Transconductance | V _{DS} =10V, I _D =15A | 18 | | | S |
| C _{iss} | Input Capacitance | V _{DS} =25V, V _{GS} =0V f=1.0MHz | | 2489 | | PF |
| C _{oss} | Output Capacitance | | | 276 | | PF |
| C _{rss} | Reverse Transfer Capacitance | | | 128 | | PF |
| Q _g | Total Gate Charge | V _{DS} =30V, I _D =15A V _{GS} =10V | | 80 | | nC |
| Q _{gs} | Gate-Source Charge | | | 19 | | nC |
| Q _{gd} | Gate-Drain Charge | | | 37 | | nC |
| Switching Times | | | | | | |
| t _{d(on)} | Turn-on Delay Time | V _{DS} =30V, R _L =2.5Ω V _{GS} =10V, R _G =3Ω | | 15 | | nS |
| t _r | Turn-on Rise Time | | | 25 | | nS |
| t _{d(off)} | Turn-Off Delay Time | | | 50 | | nS |
| t _f | Turn-Off Fall Time | | | 23 | | nS |
| Source-Drain Diode Characteristics | | | | | | |
| I _{SD} | Source-Drain Current(Body Diode) | | | 45 | | A |
| I _{SDM} | Pulsed Source-Drain Current(Body Diode) | | | 180 | | A |
| V _{SD} | Forward On Voltage ^(Note 1) | T _J =25°C, I _{SD} =1A, V _{GS} =0V | | 0.74 | 0.99 | V |
| t _{rr} | Reverse Recovery Time ^(Note 1) | T _J =25°C, I _F =15A di/dt=100A/μs | | 24 | | nS |
| Q _{rr} | Reverse Recovery Charge ^(Note 1) | | | | 30 | |
| t _{on} | Forward Turn-on Time | Intrinsic turn-on time is negligible(turn-on is dominated by L _S +L _D) | | | | |

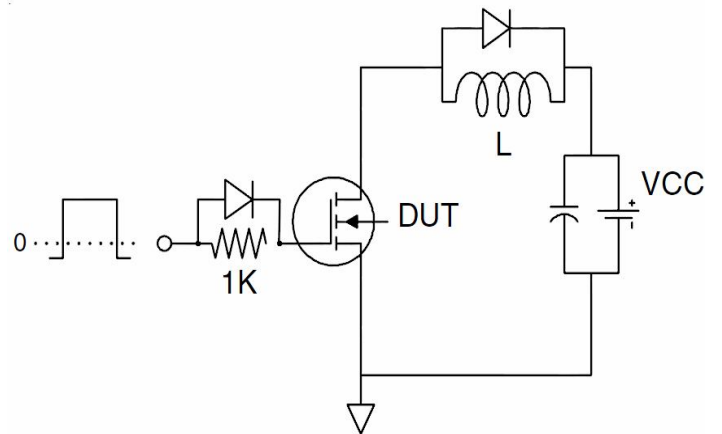
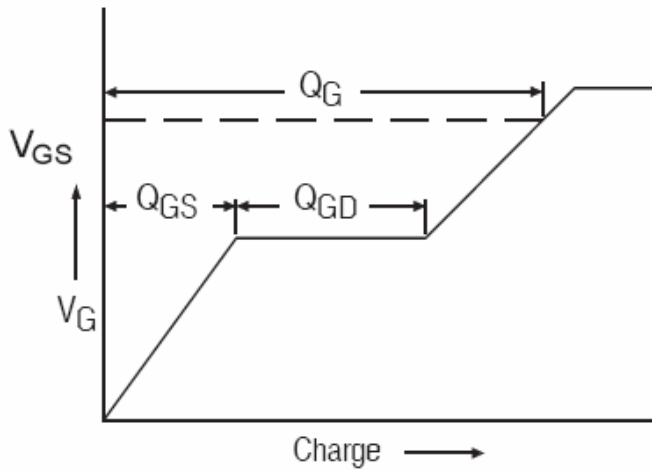
Notes 1. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 1.5%, Starting T_J=25°C

Test Circuit

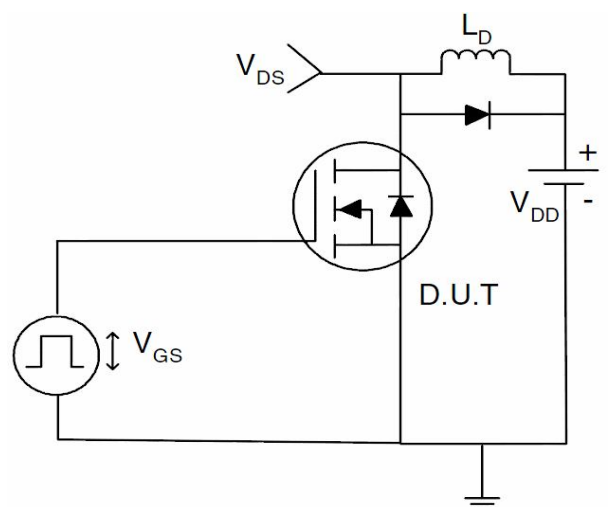
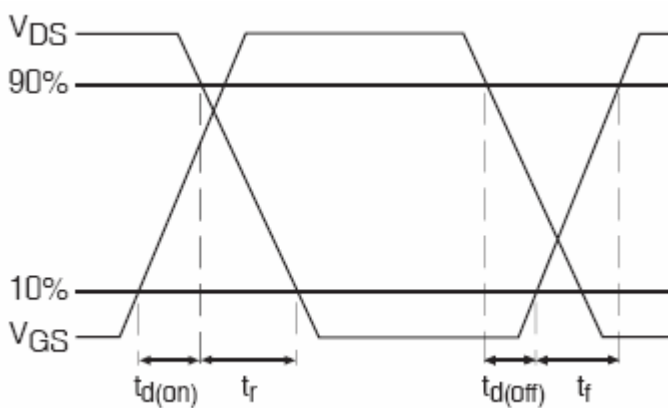
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit:



3) Switch Time Test Circuit:



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)

Figure1. Output Characteristics

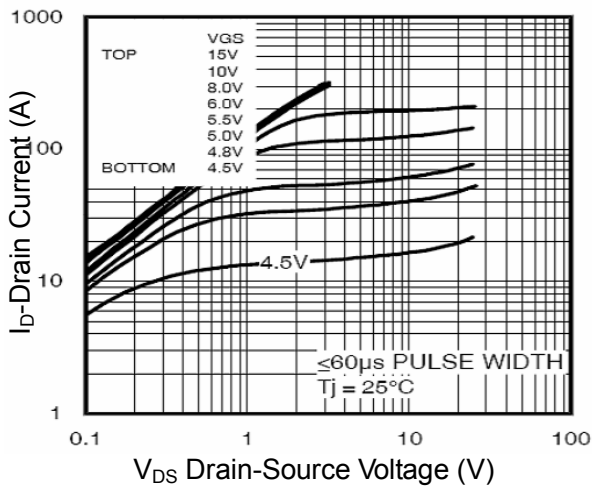


Figure2. Transfer Characteristics

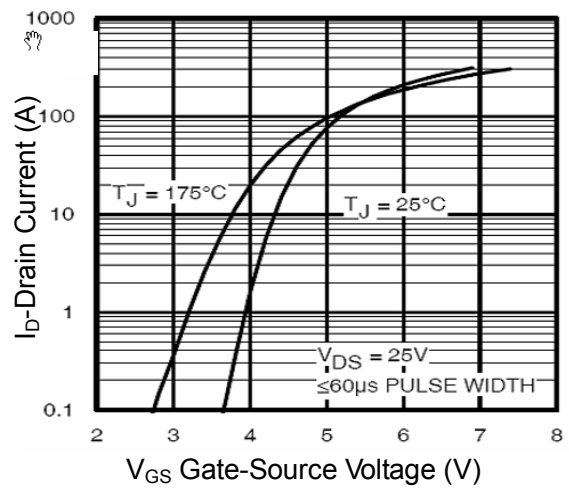


Figure3. BV_{DSS} vs Junction Temperature

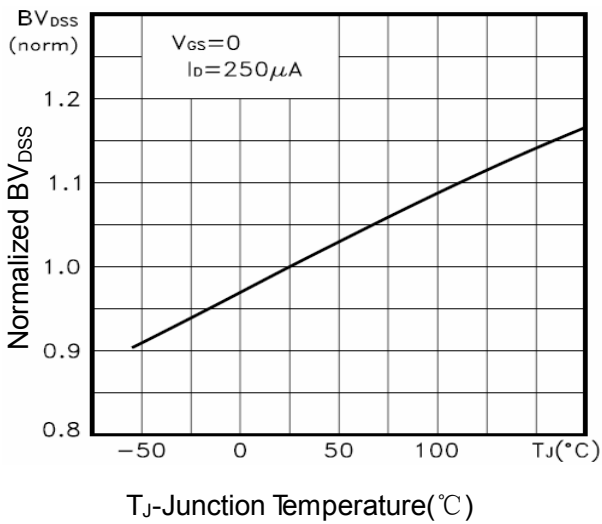


Figure4. ID vs Junction Temperature

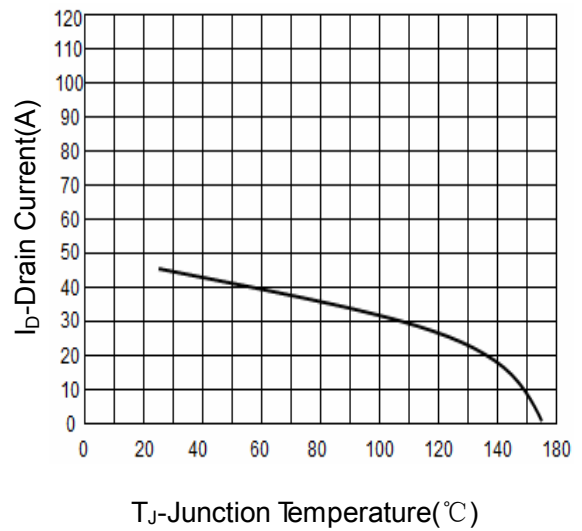


Figure5. VGS(th) vs Junction Temperature

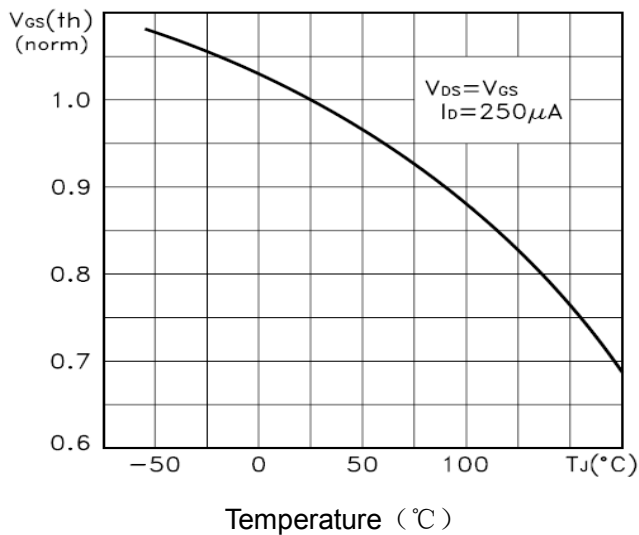


Figure6. R_{ds(on)} Vs Junction Temperature

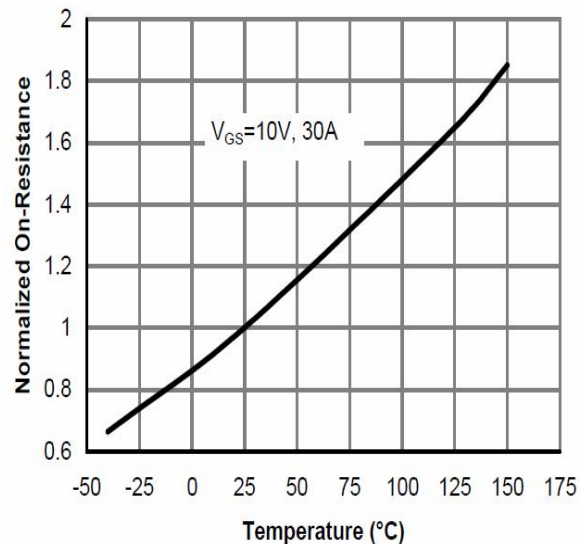


Figure7. Gate Charge

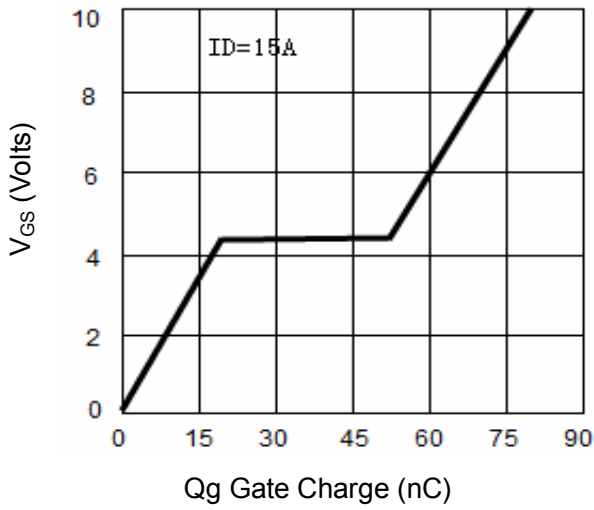


Figure8. Capacitance vs Vds

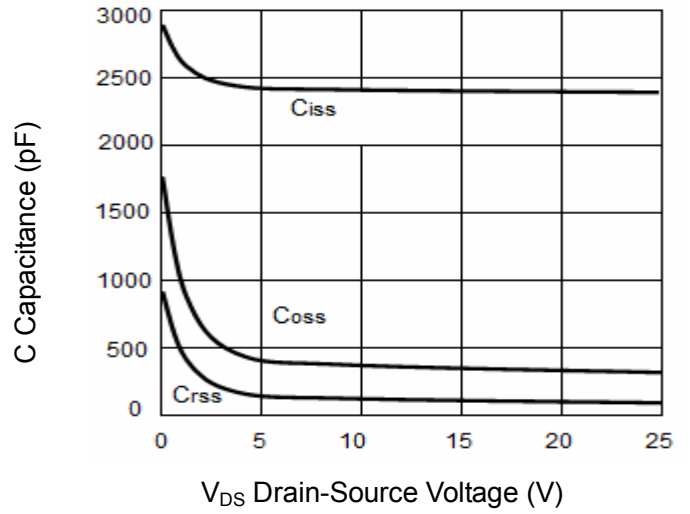


Figure9. Source- Drain Diode Forward

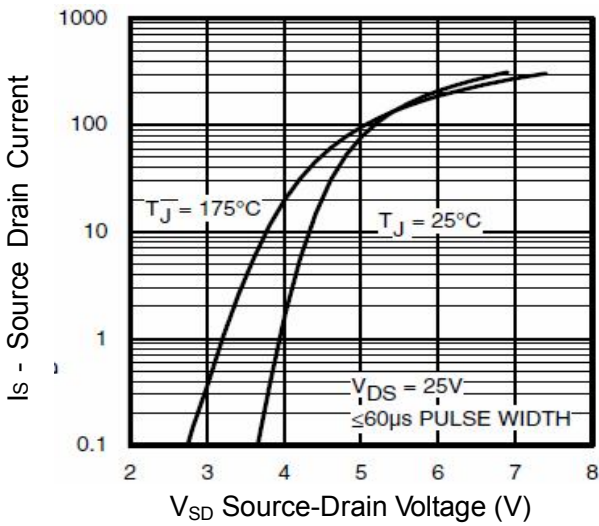


Figure10. Safe Operation Area

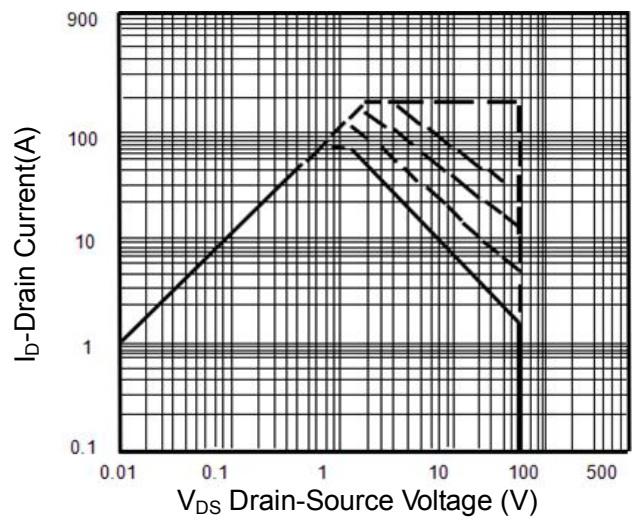
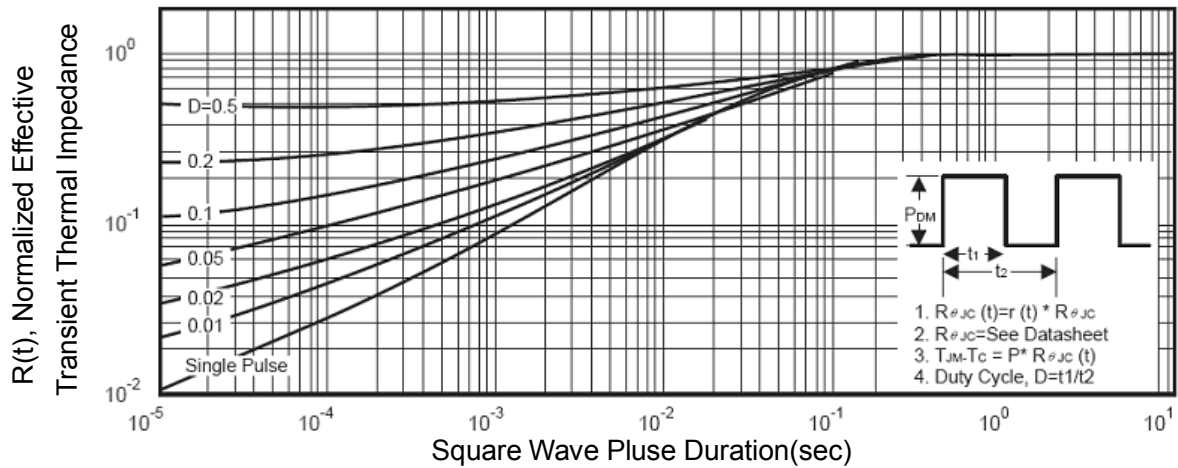
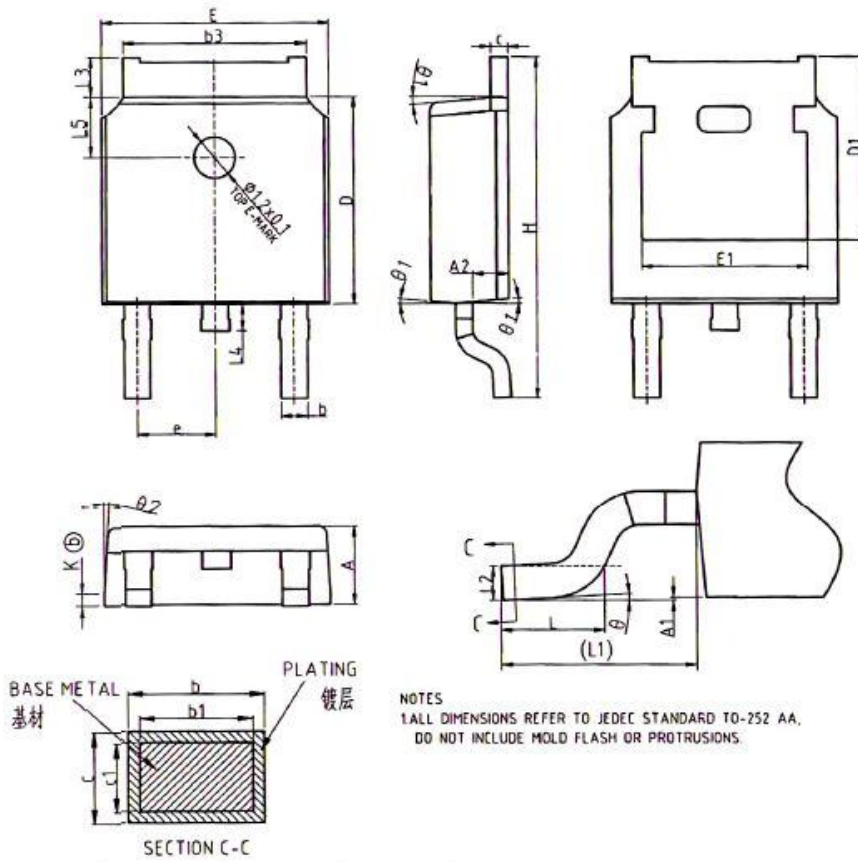


Figure11. Normalized Maximum Transient Thermal Impedance



TO-252 Package Information



NOTES
1. ALL DIMENSIONS REFER TO JEDEC STANDARD TO-252 AA.
DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS.

| COMMON DIMENSIONS | | | |
|-------------------|----------|-------|-------|
| SYMBOL | mm | | |
| | MIN | NOM | MAX |
| A | 2.20 | 2.30 | 2.38 |
| A1 | 0.00 | - | 0.10 |
| A2 | 0.97 | 1.07 | 1.17 |
| b | 0.72 | 0.78 | 0.85 |
| b1 | 0.71 | 0.76 | 0.81 |
| b3 | 5.23 | 5.33 | 5.46 |
| c | 0.47 | 0.53 | 0.58 |
| c1 | 0.46 | 0.51 | 0.56 |
| D | 6.00 | 6.10 | 6.20 |
| D1 | 5.30REF | | |
| E | 6.50 | 6.60 | 6.70 |
| E1 | 4.70 | 4.83 | 4.92 |
| e | 2.286BSC | | |
| H | 9.90 | 10.10 | 10.30 |
| L | 1.40 | 1.50 | 1.70 |
| L1 | 2.90REF | | |
| L2 | 0.51BSC | | |
| L3 | 0.90 | - | 1.25 |
| L4 | 0.60 | 0.80 | 1.00 |
| L5 | 1.70 | 1.80 | 1.90 |
| θ | 0° | - | 8° |
| θ_1 | 5° | 7° | 9° |
| θ_2 | 5° | 7° | 9° |
| K | 0.10REF | | |